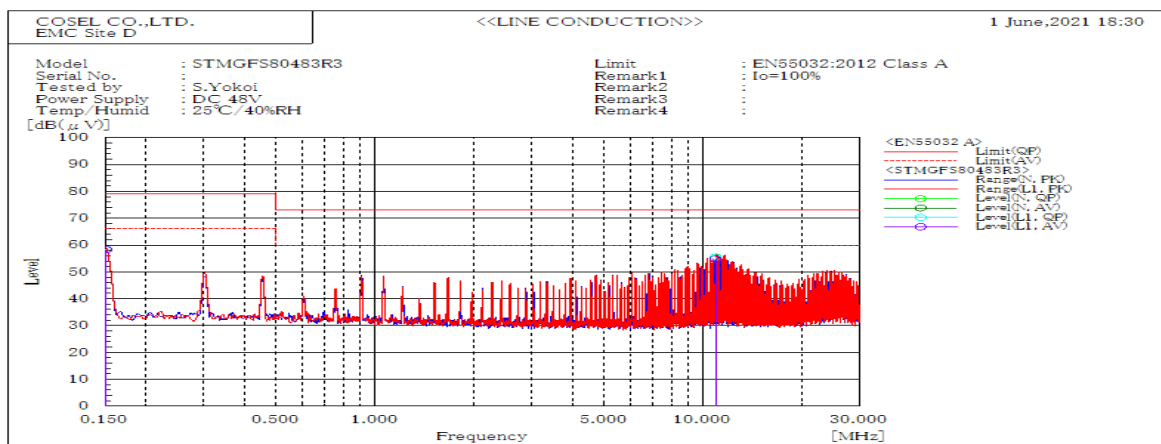
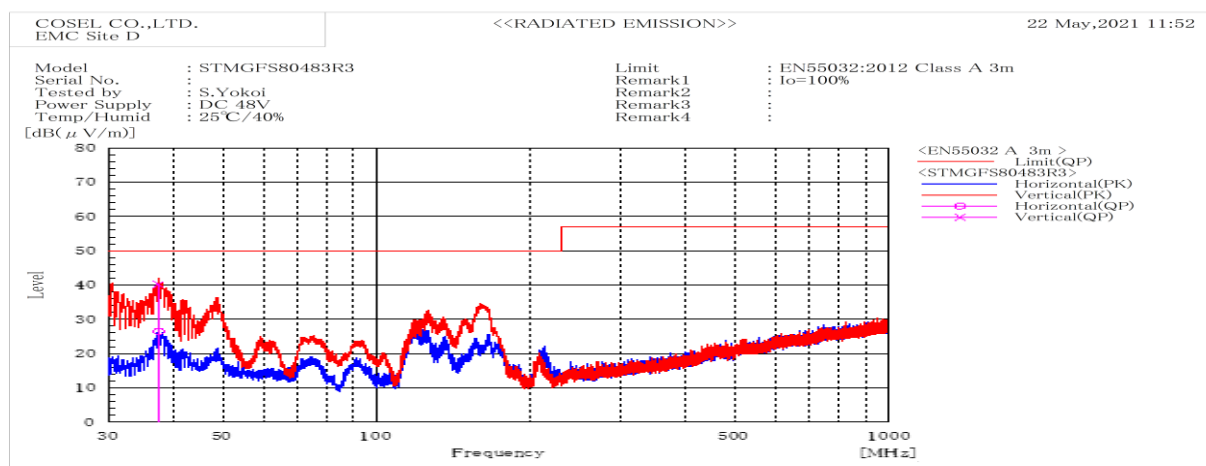


DATA SHEET		Date	08-Jul-21
Model	STMGFS80483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi



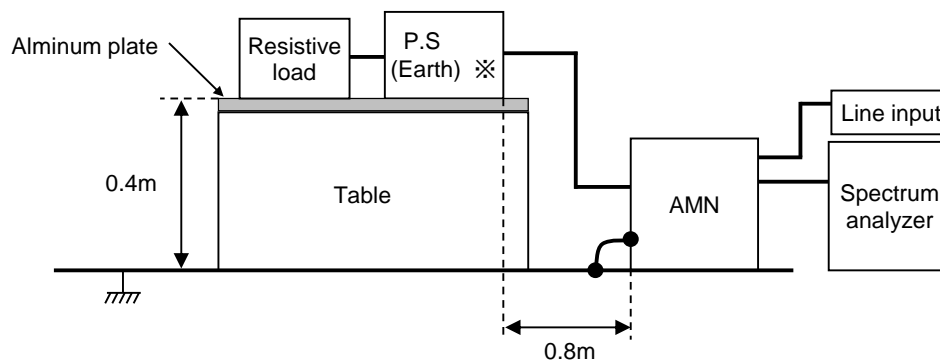
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.151	L1	58.4	58.3	79	66	20.6	7.7	Pass	
10.905	L1	55.6	54.8	73	60	17.4	5.2	Pass	
0.151	N	58.4	58.3	79	66	20.6	7.7	Pass	
10.902	N	55.5	54.9	73	60	17.5	5.1	Pass	



Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP				
37.451	V	Stable	40.2	50	9.8	Pass	100	281.3	
37.466	H	Stable	26.5	50	23.5	Pass	199.7	39.7	

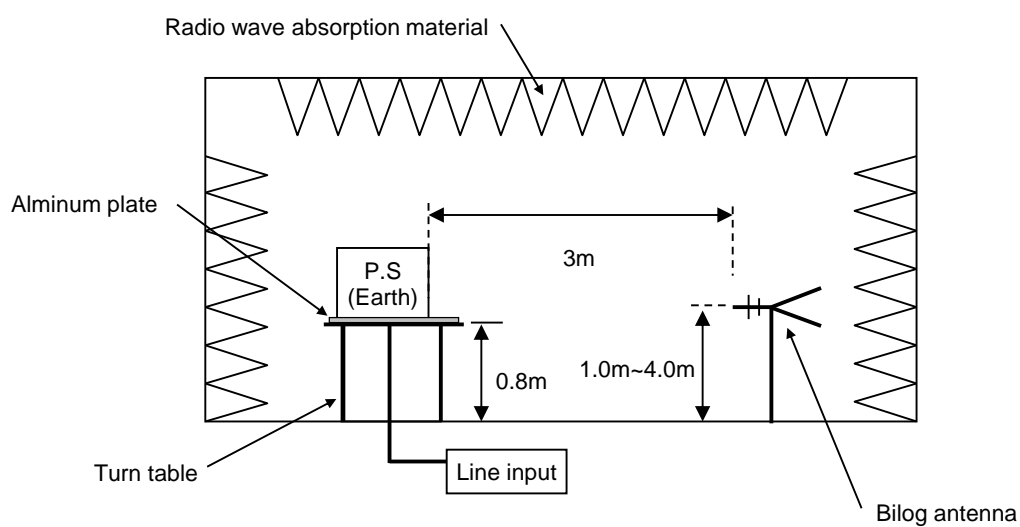
DATA SHEET		Date	08-Jul-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Yokoi

1. Line conduction



※External capacitor on the input side : 120 μ F

2. Radiated emission



Conditions

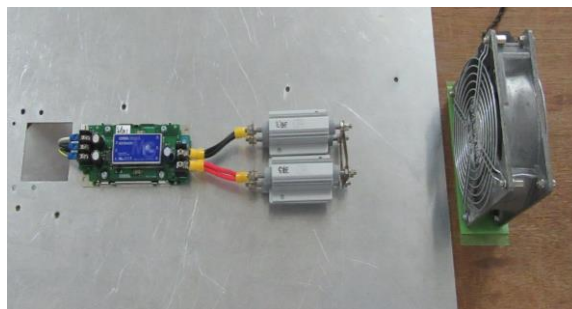
Test : EMI

Model Name : STMGFS80□□

○Photographs of Test Set-Up LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

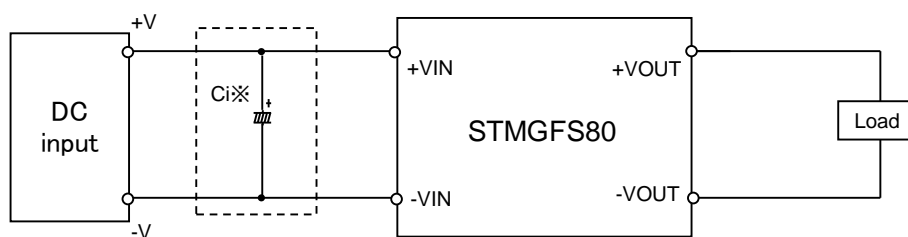


Fig.1 Testing circuitry

※Ci : External capacitor on the input side when LINE CONDUCTION

Ci : STMGFS8024□□ 220 μ F
STMGFS8048□□ 120 μ F